



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/087,558
Filing Date February 28, 2002
Inventor Ross S. Dando et al.
Assignee Micron Technology, Inc.
Group Art Unit 1763
Examiner Rudy Zervigon
Attorney's Docket No. MI22-1940
Title: Manifold Assembly for Feeding Reactive Precursors to Substrate
Processing Chambers

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the cited art are attached hereto. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: Sept 30, 2004

By: Jennifer J. Taylor

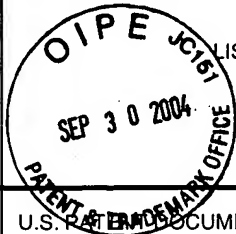
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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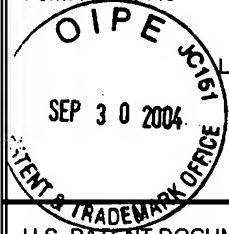
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1940		SERIAL NO. 10/087,558	
				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT: Micron Technology, Inc.			
				FILING DATE February 28, 2002		GROUP 1763	
U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	2003/0003697A1	01-2003	Agarwal et al.			Aug. 21, 2002
	AB	2003/0001190A1	01-2003	Basceri et al.			Aug. 26, 2002
	AC	2002/0037630A1	03-2002	Agarwal et al.			Oct. 29, 2001
	AD	6,787,185 B2	09-2004	Derderian et al.			
	AE	6,765,250 B2	07-2004	Doan et al.			
	AF	6,746,934 B2	06-2004	Sandhu et al.			
	AG	6,689,624 B2	02-2004	Doan et al.			
	AH	6,653,154 B2	11-2003	Doan et al.			
	AI	6,627,260 B2	09-2003	Derderian et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AJ						
	AK						
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AM						
	AN						
	AO						
EXAMINER		DATE CONSIDERED					
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,596,636 B2	07-2003	Sandhu et al.			
	AB	6,596,583 B2	07-2003	Agarwal et al.			
	AC	6,559,472 B2	05-2003	Sandhu et al.			
	AD	6,541,353 B1	04-2003	Sandhu et al.			
	AE	6,534,357 B1	03-2003	Basceri et al.			
	AF	6,458,416 B1	10-2002	Derderian et al.			
	AG	6,420,230 B1	07-2002	Derderian et al.			
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	AI	6,143,659	11-2000	Leem			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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Form PT 0-149 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1940		SERIAL NO. 10/087,558	
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FILING DATE February 28, 2002				GROUP 1763			

U.S. PATENT DOCUMENTS							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,478,872 B1	11-2002	Chae et al.			
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	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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